S1 Series



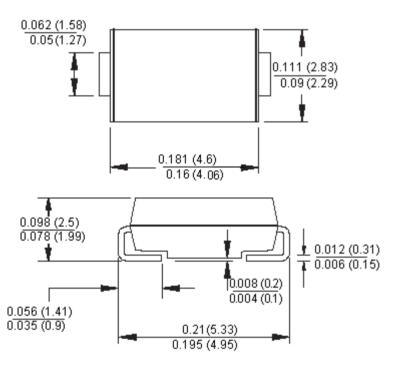


Features:

- For surface mounted application
- Glass passivated junction chip
- Low forward voltage drop
- High current capability
- Easy pick and place
- High surge current capability
- Plastic material
- High temperature soldering: 260°C / 10 seconds at terminals
- High reliability grade (AEC Q101 qualified)



SMA/DO-214AC



Dimensions: Inches (Millimetres)

Mechanical Data

Cases : Moulded plastic

Terminals : Pure tin plated, lead free solderable per J-STD-002B and JESD22-B102D

Polarity : Indicated by cathode band Packing : 12 mm tape per EIA STD RS-481

Weight : 0.064 g



S1 Series



Maximum Ratings and Electrical Characteristics

Rating at 25°C ambient temperature unless otherwise specified. Single phase, half wave, 60 Hz, resistive or inductive load. For capacitive load, derate current by 20%

Type Number	Symbol	S1K	S1M	Units
Maximum Recurrent Peak Reverse Voltage	V_{RRM}	800	1,000	V
Maximum RMS Voltage	V _{RMS}	560	700	
Maximum DC Blocking Voltage	V _{DC}	800	1,000	
Maximum Average Forward Rectified Current T _L = 110°C	I _(AV)	1		- A
Peak Forward Surge Current, 8.3 ms Single Half Sine-wave Superimposed on Rated Load (JEDEC method)	I _{FSM}	30		
Maximum Instantaneous Forward Voltage at 1 A	V _F	1.1		V
Maximum DC Reverse Current at T _A = 25°C at Rated DC Blocking Voltage at T _A = 125°C	I _R	1 50		μА
Maximum Reverse Recovery Time (Note 1)	T _{rr}	1.5		uS
Typical Junction Capacitance (Note 2)	Cj	12		pF
Non-Repetitive Peak Reverse Avalanche Energy at 25°C, I _{AS} = 1 _A , L = 10 mH	E _{AS}	5		mJ
Typical Thermal Resistance (Note 3)	R _{θJL} RθJA	30 85		°C / W
Operating Temperature Range	ТЈ	-55 to +150		°C
Storage Temperature Range	T _{STG}			

Notes : 1. Reverse recovery test conditions : I_F = 0.5 A, I_R = 1 A, I_{RR} = 0.25 A

2. Measured at 1 MHz and applied $V_R = 4 V$

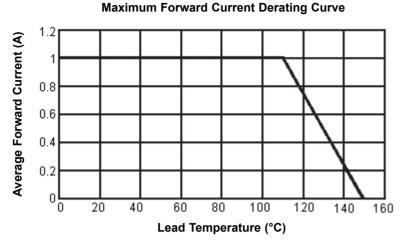
3. Measured on PC board with 0.2×0.2 inches (5 × 5) copper pad areas

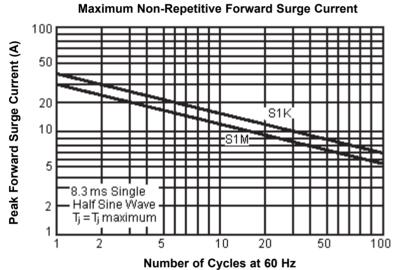


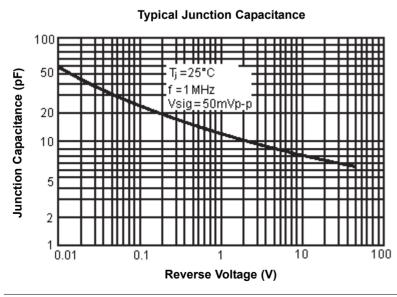
S1 Series

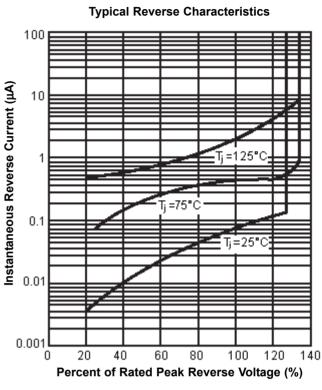


Ratings and Characteristic Curves (S1K and S1M)

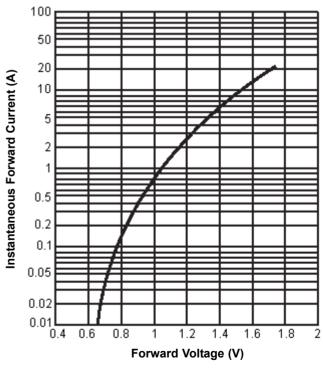












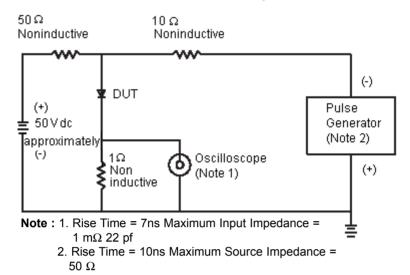
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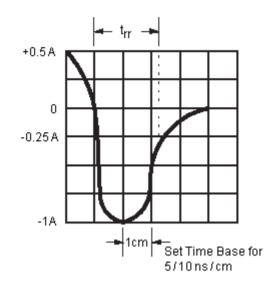


S1 Series



Reverse Recovery Time Characteristic and Test Circuit Diagram





Part Number Table

Description	Part Number	
Diode, Standard, 1 A, 800 V	S1K	
Diode, Standard, 1 A, 1,000 V	S1M	

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